# Power MOSFET

## 30 V, 7.5 A, Dual N-Channel, SOIC-8

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Dual SOIC-8 Surface Mount Package Saves Board Space
- This is a Pb-Free Device

#### **Applications**

- Disk Drives
- DC-DC Converters
- Printers

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Rating			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Voltage			$V_{GS}$	±20	V
Continuous Drain		$T_A = 25^{\circ}C$	ΙD	5.5	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 70°C		4.4	
Power Dissipation R <sub>0JA</sub> (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	1.14	W
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	4.5	Α
Current R <sub>θJA</sub> (Note 2)	Steady	T <sub>A</sub> = 70°C		3.5	
Power Dissipation R <sub>0</sub> JA (Note 2)	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	0.68	W
Continuous Drain	1	T <sub>A</sub> = 25°C	I <sub>D</sub>	7.5	Α
Current $R_{\theta JA}$ t < 10 s (Note 1)		T <sub>A</sub> = 70°C		6.0	
Power Dissipation R <sub>0</sub> J <sub>A</sub> t < 10 s (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	1.95	W
Pulsed Drain Current	$T_A = 25^{\circ}C,$ $t_p = 10 \mu s$		I <sub>DM</sub>	30	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	–55 to +150	ç
Source Current (Body Diode)			I <sub>S</sub>	2.0	Α
Single Pulse Drain-to-Source Avalanche Energy $T_J$ = 25°C, $V_{DD}$ = 30 V, $V_{GS}$ = 10 V, $I_L$ = 7.5 $A_{pk}$ , $L$ = 1.0 mH, $R_G$ = 25 $\Omega$			EAS	28	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

#### THERMAL RESISTANCE RATINGS

Rating	Symbol	Max	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	110	
Junction–to–Ambient – t≤10 s (Note 1)	$R_{\theta JA}$	64	°C/W
Junction-to-FOOT (Drain)	$R_{\theta JF}$	40	0,00
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	183.5	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surface-mounted on FR4 board using 1 inch sq pad size, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.

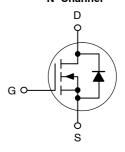


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V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> Max	I <sub>D</sub> Max
30 V	24 mΩ @ 10 V	7.5 A
	36 mΩ @ 4.5 V	7.671

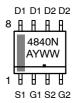
#### N-Channel



## MARKING DIAGRAM & PIN ASSIGNMENT



SOIC-8 CASE 751 STYLE 11



4840N = Device Code
A = Assembly Location
Y = Year
WW = Work Week
• = Pb-Free Package

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMD4840NR2G	SOIC-8 (Pb-Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)jk

Characteristic	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Tem- perature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				18		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			1.0	
		V <sub>DS</sub> = 24 V	T <sub>J</sub> = 100°C			10	- μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{G}$	<sub>S</sub> = ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μA	1.5		3.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				6.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 6.9 A		16	24	0
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 5.0 A		26	36	mΩ
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 1.5 V, I	<sub>D</sub> = 6.9 A		15		S
CHARGES, CAPACITANCES AND GATE F	ESISTANCE						•
Input Capacitance	C <sub>ISS</sub>				520		
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1.0 M	IHz, V <sub>DS</sub> = 15 V		140		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>	1			70		
Total Gate Charge	Q <sub>G(TOT)</sub>				4.8		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> =	15 // 1 6 0 4		1.1		
Gate-to-Source Charge	$Q_{GS}$	v <sub>GS</sub> = 4.5 v, v <sub>DS</sub> =	15 V, ID = 0.9 A		2.1		
Gate-to-Drain Charge	$Q_{GD}$	1			1.9		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 6.9 A			9.5		nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t <sub>d(ON)</sub>				7.6		
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V, V <sub>[</sub>	<sub>OD</sub> = 15 V,		5.0		1
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 1.0 \text{ A}, R_G = 3.0 \Omega$			17		ns
Fall Time	t <sub>f</sub>	1			3.0		1
DRAIN-TO-SOURCE CHARACTERISTICS	1						
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V	T <sub>J</sub> = 25°C		0.76	1.0	V
		I <sub>D</sub> = 2.0 A	T <sub>J</sub> = 125°C		0.58		1
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } d_{IS}/d_t = 100 \text{ A/}\mu\text{s,}$ $I_S = 2.0 \text{ A}$			12.5		1
Charge Time	Ta				7.3		ns
Discharge Time	T <sub>b</sub>				5.2		
Reverse Recovery Time	Q <sub>RR</sub>				6.0		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			0.66		nH
Drain Inductance	L <sub>D</sub>				0.20		nH
Gate Inductance	L <sub>G</sub>				1.50		nH
Gate Resistance	$R_{G}$				2.0	3.0	Ω

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

#### TYPICAL PERFORMANCE CURVES

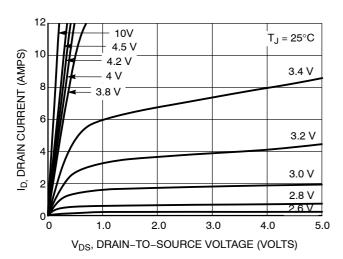
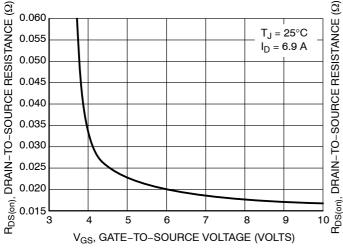


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



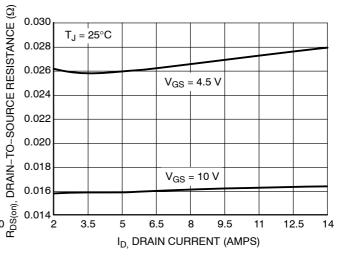
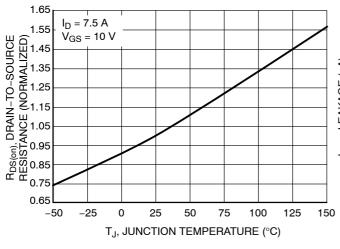


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



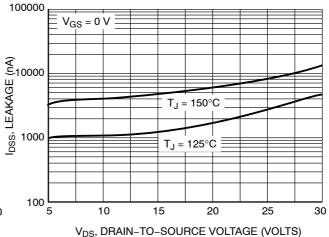


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### TYPICAL PERFORMANCE CURVES

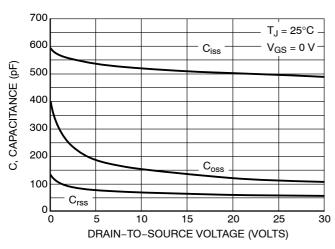


Figure 7. Capacitance Variation

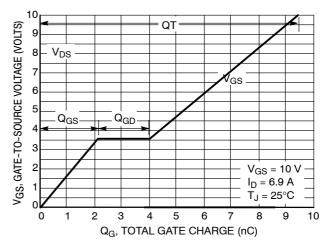


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

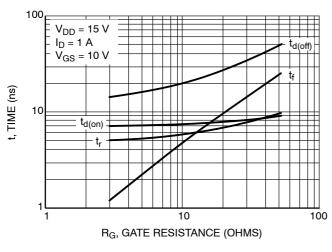


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

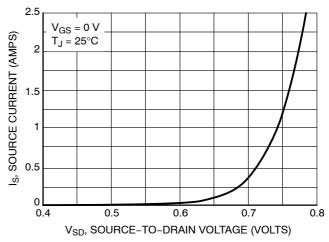


Figure 10. Diode Forward Voltage vs. Current

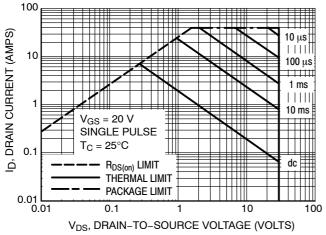


Figure 11. Maximum Rated Forward Biased Safe Operating Area

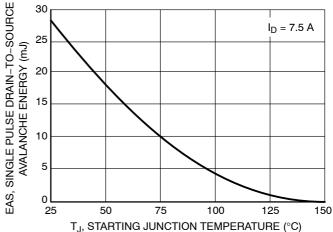
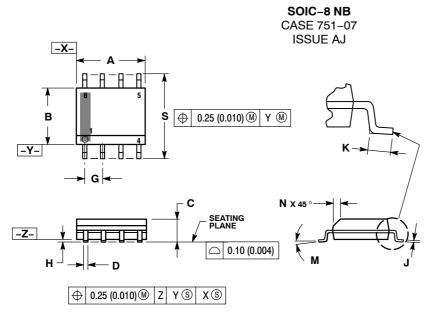
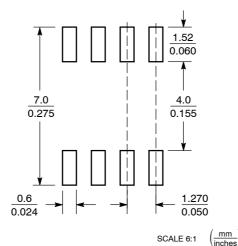


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

#### PACKAGE DIMENSIONS



#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering Mounting Techniques Reference Manual, SOLDERRM/D.

#### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION A AND B DO NOT INCLUDE
- MOLD PROTRUSION.
  MAXIMUM MOLD PROTRUSION 0.15 (0.006)
- PER SIDE.

  DIMENSION D DOES NOT INCLUDE DAMBAR
- PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT
- MAXIMUM MATERIAL CONDITION. 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07

	MILLIMETERS		INC	HES		
DIM	MIN	MAX	MIN	MAX		
Α	4.80	5.00	0.189	0.197		
В	3.80	4.00	0.150	0.157		
С	1.35	1.75	0.053	0.069		
D	0.33	0.51	0.013	0.020		
G	1.27	1.27 BSC		50 BSC		
Н	0.10	0.25	0.004	0.010		
J	0.19	0.25	0.007	0.010		
K	0.40	1.27	0.016	0.050		
M	0 °	8 °	0 °	8 °		
N	0.25	0.50	0.010	0.020		
S	5.80	6.20	0.228	0.244		

#### STYLE 11:

- PIN 1. SOURCE 1
  - GATE 1 2.
  - SOURCE 2
  - GATE 2 DRAIN 2
  - DRAIN 2 6.
  - DRAIN 1
  - DRAIN 1

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